



**WANSEMI**  
万芯半导体

**WP16N65FA**

# **Enhancement Mode N-Channel Power MOSFET**

TO-220F/NMOS/650V/ $\pm 30$ V/3V/16A/450m $\Omega$

Rev0.7

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## Enhancement Mode N-Channel Power MOSFET

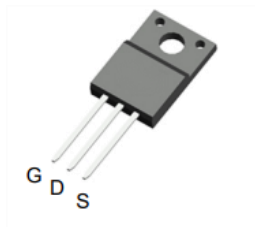
### 1.Features

- ◆ Fast Switching
- ◆ Improved dv/dt Capability

### 2.Applications

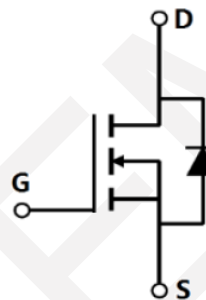
- ◆ Load Switch
- ◆ PWM Application
- ◆ Power management

$V_{DS}$	$R_{DS(on)}$ Typ.	$I_D$ Max.
650V	450m $\Omega$ @ 10V	16A



Pin Description

TO-220F



Schematic Diagram

### 3.Package Marking and Ordering Information

Part no.	Marking	Package	PCS/Tube	PCS/CTN.
WP16N65FA	WP16N65	TO-220F	50	5,000

### 4.Absolute Max Ratings at Ta=25°C (Note1)

Parameter	Symbol	Value	Units
Drain to Source Voltage	$V_{DS}$	650	V
Gate to Source Voltage	$V_{GS}$	$\pm 30$	V
Drain Current (DC)	$I_D$	16	A
Drain Current (Pulse), $PW \leq 300\mu s$	$I_{DP}$	64	A
Total Dissipation	$P_D$	98	W
Avalanche Energy, Single Pulsed	$E_{AS}$	461	mJ
Junction Temperature	$T_j$	150	$^{\circ}C$
Storage Temperature	$T_{stg}$	-55 to +150	$^{\circ}C$

Note 1: Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

### 5. Thermal Resistance Ratings

Parameter	Symbol	Value	Unit
Junction to case	$R_{\theta JC}$	1.3	$^{\circ}C/W$
Junction to ambient	$R_{\theta JA}$	62.5	$^{\circ}C/W$

Note 2: When mounted on 1 inch square copper board  $t \leq 10$ sec The value in any given application depends on the user's specific board design.

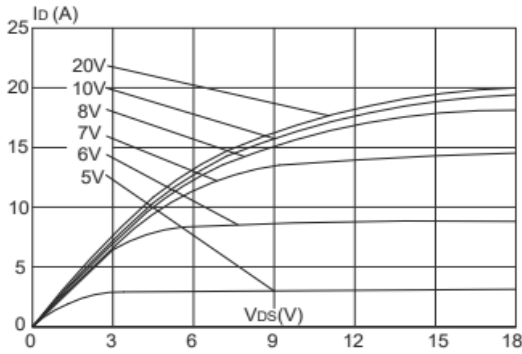
### 6. Electrical Characteristics at $T_a=25^{\circ}C$ (Note 3)

Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Drain to Source Breakdown Voltage	$V_{(BR)DSS}$	$I_D = 250\mu A, V_{GS} = 0V$	650	693	-	V
Zero-Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = 650V, V_{GS} = 0V$	-	-	1	$\mu A$
Gate to Source Leakage Current	$I_{GSS}$	$V_{GS} = \pm 30V$	-	-	$\pm 100$	nA
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS}, I_{DS}=250\mu A$	2	3	4	V
Static Drain to Source On-State Resistance	$R_{DS(on)}$	$I_D = 8A, V_{GS} = 10V$	-	0.45	0.6	$\Omega$
Input Capacitance	$C_{iss}$	$V_{GS}=0V,$ $V_{DS}=325V,$ Frequency=1.0MHz	-	2740	-	pF
Output Capacitance	$C_{oss}$		-	214	-	pF
Reverse Transfer Capacitance	$C_{rss}$		-	15	-	pF
Turn-ON Delay Time	$t_{d(on)}$	$I_D = 16A, V_{DS}$ $=325V, R_{GEN}= 25\Omega$	-	35	-	ns
Rise Time	$t_r$		-	50	-	ns
Turn-OFF Delay Time	$t_{d(off)}$		-	160	-	ns
Fall Time	$t_f$		-	65	-	ns
Total Gate Charge	$Q_g$	$V_{DS} = 520V,$ $V_{GS} = 10V,$ $I_D = 16A$	-	71	-	nC
	$Q_{gs}$		-	10	-	nC
	$Q_{gd}$		-	32	-	nC
Diode Forward Voltage	$V_{FSD}$	$I_{SD} = 16A, V_{GS} = 0V$	0.5	0.8	1.0	V

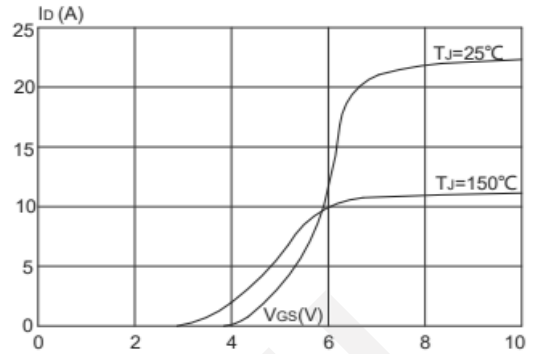
Note 3: Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.



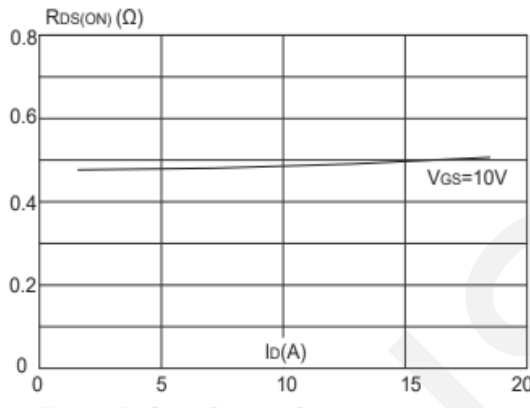
### 7. Typical electrical and thermal characteristics



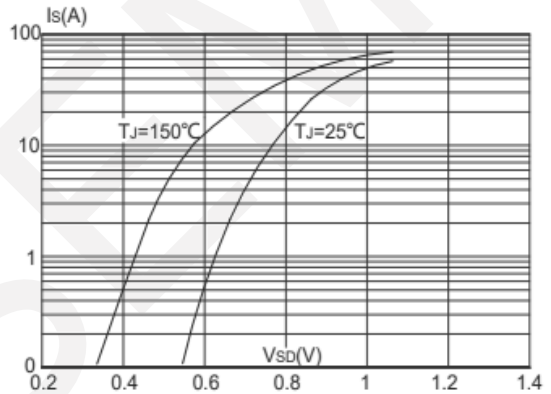
Output Characteristics



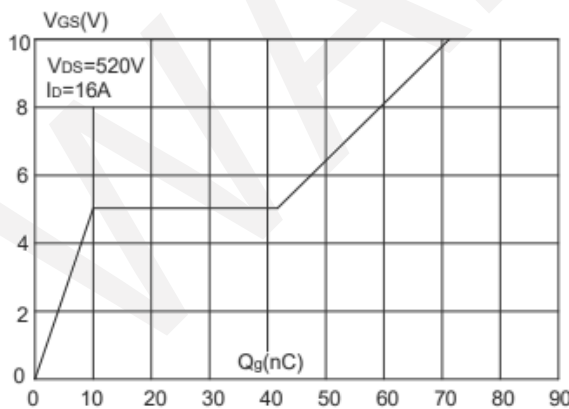
Transfer Characteristics



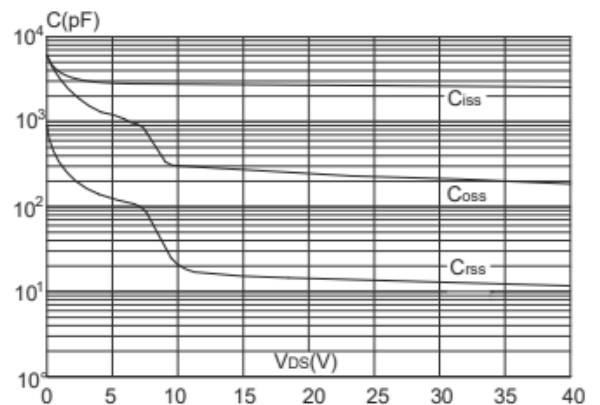
Rdson-Drain Current



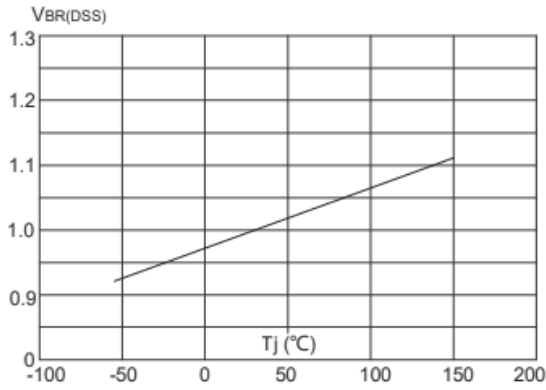
Body Diode Characteristic



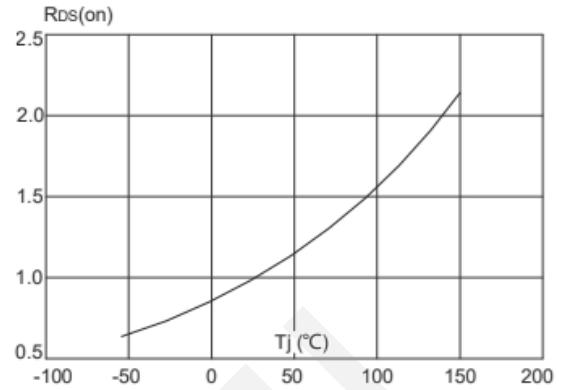
Gate Charge



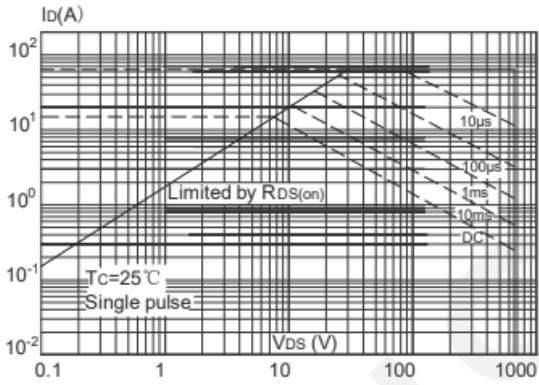
Capacitance Characteristics



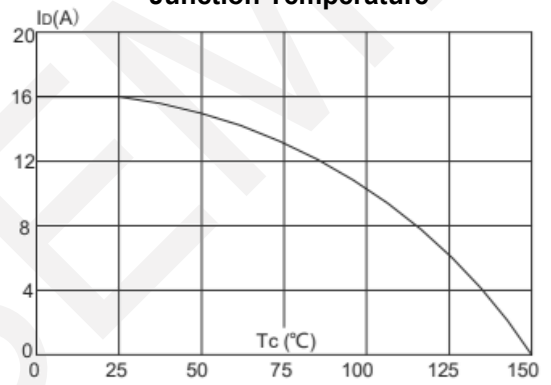
**Normalized Breakdown Voltage vs. Junction Temperature**



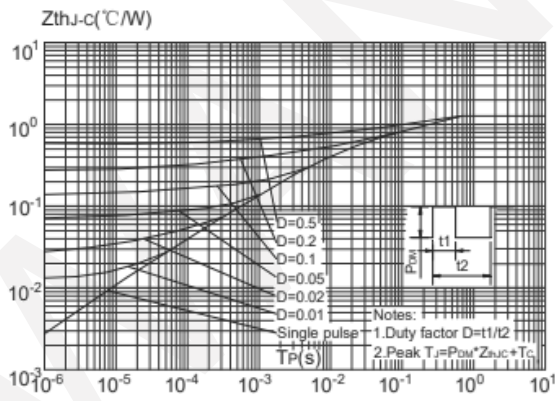
**Normalized on Resistance vs. Junction Temperature**



**Maximum Safe Operating Area**



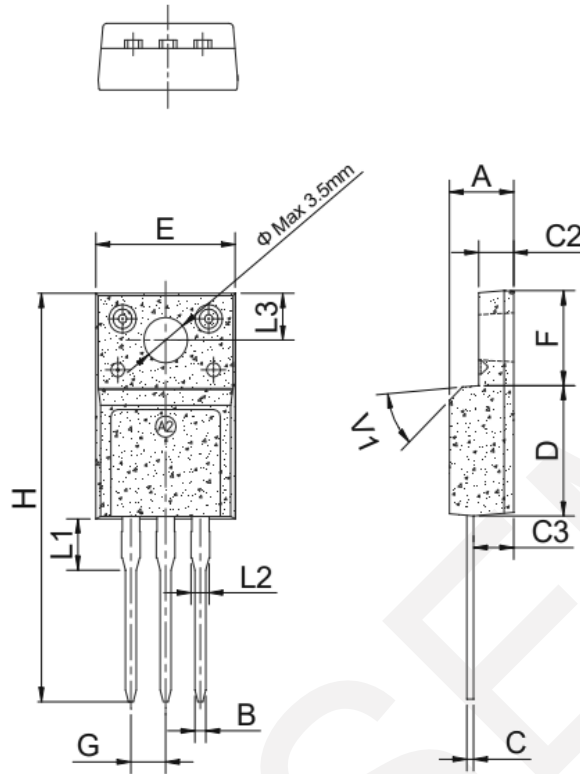
**Maximum Continuous Drain Current vs. Case Temperature**



**Maximum Effective Transient Thermal Impedance, Junction-to-Case**



**8.Package Dimensions**



Ref.	Dimensions					
	Millimeters			Inches		
	Min.	Typ.	Max.	Min.	Typ.	Max.
A	4.50		4.90	0.177		0.193
B	0.74	0.80	0.83	0.029	0.031	0.033
C	0.47		0.65	0.019		0.026
C2	2.45		2.75	0.096		0.108
C3	2.60		3.00	0.102		0.118
D	8.80		9.30	0.346		0.366
E	9.80		10.4	0.386		0.410
F	6.40		6.80	0.252		0.268
G		2.54			0.1	
H	28.0		29.8	1.102		1.173
L1		3.63			0.143	
L2	1.14		1.70	0.045		0.067
L3		3.30			0.130	
V1		45°			45°	

## 9. Important Notice

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